

# INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

Docket Number (Optional)

BU9-99-152 (12769)

Application Number

Unassigned

Applicant(s)

Edward W. Conrad, et al.

Filing Date

Herewith

Group Art Unit

Unassigned

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

10/11 U.S. PTO  
09/512570  
02/28/00

## FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
TYL		61-88440	5/6/86	Japan				
TYL		62-105006	5/15/87	Japan				
TYL		8-136236	5/31/96	Japan				

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

TYL		(1978), E-Beam Line Width And Pattern Location Measurement Tool", IBM Technical Disclosure Bulletin, Vol. 21, No. 1, pp. 151.
TYL		E. Coombs, et al., (1991), "Two-Dimensional Atomic Force Microprobe Trench Metrology System", J. Vac. Sci. Technol., Vol. B9, No. 6, pp. 3612-3616.

EXAMINER

*Tommy Lee*

DATE CONSIDERED

12/23/2002

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.